

**REMARKS**

The present application includes claims 1-19 and 21. Claim 20 has been withdrawn. Claims 10 and 12-19 were rejected by the Examiner. Claim 11 has been objected to by the Examiner. Claims 1-9 and 21 have been allowed by the Examiner. By this response, claims 11 and 18 have been amended as independent claims.

In accordance with the Examiner's statement in the Office Action of September 9, 2005, claims 11 and 18 have been rewritten in independent form including all of the limitations of their base claim 10. The Applicant respectfully requests allowance of independent claims 11 and 18, as well as dependent claim 19, which depends from claim 18.

Claims 10 and 12-19 were rejected under 35 U.S.C. § 112, first paragraph, as being not enabled by the specification without the use of a multipin phantom. However, claim 18 does include mention of a multipin phantom. By this response, claim 18 has been rewritten in independent form, and the Applicant respectfully submits that claim 18 and its dependent claim 19 should be allowable as the Examiner has indicated an independent claim 11 would be allowable.

Additionally, the Examiner states that the specification does not enable any person skilled in the art to which it pertains, or to which it is most nearly connected, to practice the invention commensurate in scope with claims 10 and 12-19. The Examiner states that the invention requires imaging a multipin phantom and that the array of detectors is irradiated by an x-ray beam and not electrons. The Applicant respectfully disagrees with these characterizations.

Figures 7 and 8 of the present application illustrate an electron beam tuning system 700 formed in accordance with an embodiment of the present invention and a flow diagram 800 for a method for adjusting an electron beam used in accordance with an embodiment of the present invention, respectively. Thus, the specification clearly envisions application to an electron beam as well as to an x-ray beam.

Furthermore, the disclosure in the application with respect to Figures 7 and 8, from paragraph [56] to paragraph [68], illustrates a scope of operation including a multipin phantom and beyond. Figure 7 uses a multipin phantom purely as an example but does not rely solely on the use of a multipin phantom to correct a radius of a motion pattern of an electron beam based on variation of the radius from a desired radius over time. Additionally, the discussion of the system 700 and Figure 7 does not rely solely on the use of a multipin phantom to adjusting an angle of the motion pattern of the electron beam based on variation of position of the motion pattern from a desired position over time. (See, e.g., paras. [58]-[62]). In addition, Figure 8 describes an embodiment of a motion for adjusting an electron beam without mention of a multipin phantom at all. (See, paras. [63]-[67]). Therefore, the Applicant submits that claim 10 and dependent claims 12-17 are in condition for allowance. The Examiner had previously indicated that claims 10 and 12-17 were allowable, and action to that affect is respectfully requested.

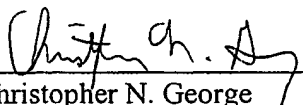
**CONCLUSION**

The Applicants submit that the present application is in condition for allowance. If the Examiner has any questions or the Applicants can be of any assistance, the Examiner is invited and encouraged to contact the Applicants at the number below. In particular, should the Examiner have any questions concerning the definiteness of the claims in pointing out and distinctly claiming the subject matter which the Applicants regard as the invention, the Examiner is invited and encouraged to contact the Applicants at the number below.

The Commissioner is authorized to charge any additional fees or credit overpayment to the Deposit Account of GTC, Account No. 070845.

Respectfully submitted,

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